PCN Number:		20	20131028000A			PCN Date:	04/11/2016		
		of Carsem Suzhou (CSZ) as Additional Assem PR/SON package		mbly and Test	Site for Select				
Cust	omer	Contact:	PC	N Ma	nager	Dept:	Qu	ality Services	
Cha	nge T	ype:			· · · ·		· · · · · · · · · · · · · · · · · · ·		
\square		mbly Site			Assembly Process		Assembly Mat	terials	
	Desi	gn			Electrical Specification		Mechanical S		
\boxtimes	Test	Site		\boxtimes	Packing/Shipping/Labeling		Test Process		
	Wafe	er Bump Site			Wafer Bump Material		Wafer Bump I	Process	
	Wafe	er Fab Site			Wafer Fab Materials		Wafer Fab Pro	ocess	
					Part number change				
					PCN Details				
		on of Change							
highl Qual QFN/ Test	Revision A is to remove select devices in the Product Affected Section (with strikethrough) and highlighted in yellow. These devices were inadvertently added and not affected by this change. Qualification of Carsem Suzhou (CSZ) as Additional Assembly and Test Site for Select Devices on QFN/SON package. Test coverage, insertions, conditions will remain consistent with current testing and verified with								
test									
Reas	son fo	or Change:							
Cont	inuity	of supply.							
Anti	cipate	ed impact on	Fo	rm,	Fit, Function, Quality or Re	liabili	ty (positive /	negative):	
None	9								
Cha	naes	to product id	en	tific	ation resulting from this PC	N:			
		y Site							
		ailand			Assembly Site Origin (22L)	ASO:	NSF	
	Malay				Assembly Site Origin (221		ASO:		
		- Philippines			Assembly Site Origin (221		ASO:		
		Suzhou			Assembly Site Origin (22L		ASO:		
Sample product shipping label (not actual product label) We Texas INSTRUMENTS MADE IN: Malaysia 2DC: 20: MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04 OPT: ITEM: 39 UBL: 5A (L)T0:1750 UDL 2000 (D) 0336 (31T) L0T: 3959047MLA (4W) TKY (1T) 7523483S12 (P) (2P) REV: (V) 0033317 (20L) CS0: SHE (21L) CC0:USA (2L) AS0: MLA (23L) AC0: MYS									
A22	PENRL	T SHE CODES	5: I	NSE	=J, TI-Malaysia = K , TI-Cl	агк = .	i, Carsem Suzh	iou = F	

Product Affected:	Product Affected:				
BQ24072RGTR	BQ24314ADSGT	SN1004052RTER	TPS51461RGET		
BQ24072RGTRG4	BQ24314ADSGTG4	TLV62065DSGR	TPS51462RGER		
BQ24072RGTT	BQ24314DSGR	TLV62065DSGT	TPS51462RGET		
BQ24072RGTTG4	BQ24314DSGRG4	TPS2540ARTER	TPS53311RGTR		
BQ24075RGTR	BQ24314DSGT	TPS2540ARTET	TPS53311RGTT		
BQ24075RGTRG4	BQ24314DSGTG4	TPS2541ARTER	TPS53312RGTR		
BQ24075RGTT	BQ24315DSGR	TPS2541ARTET	TPS53312RGTT		
BQ24075RGTTG4	BQ24315DSGRG4	TPS2541RTER	TPS54319RTER		
BQ24210DQCR	BQ24315DSGT	TPS2541RTET	TPS54319RTET		
BQ24210DQCT	BQ24315DSGTG4	TPS2546RTER	TPS62065DSGR		
BQ24300DSGR	BQ24316DSGR	TPS2546RTET	TPS62065DSGT		
BQ24300DSGRG4	BQ24316DSGRG4	TPS2554DRCR	TPS62090RGTR		
BQ24300DSGT	BQ24316DSGT	TPS2554DRCT	TPS62090RGTT		
BQ24300DSGTG4	BQ24316DSGTG4	TPS2560DRCR	TPS62091RGTR		
BQ24304DSGR	FX006	TPS2560DRCT	TPS62091RGTT		
BQ24304DSGRG4	FX016	TPS51200DRC/2801	TPS62092RGTR		
BQ24304DSGT	HPA00512DRCR	TPS51200DRCR	TPS62092RGTT		
BQ24304DSGTG4	HPA00810RGTR-1/2	TPS51200DRCR/2801	TPS62093RGTR		
BQ24313DSGR	HPA00935RGTR	TPS51200DRCRG4	TPS62093RGTT		
BQ24313DSGT	HPA01187DSGR	TPS51200DRCT			
BQ24314ADSGR	SN0803054DRCR	TPS51200DRCTG4			
BQ24314ADSGRG4	SN0803054DRCRG4	TPS51461RGER			

Qualification Data

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.						
Qual	Vehicle # 1: TPA31	17D2RHBR (MSL2-26	0C)			
Package Construction Details						
Assembly Site:	CARSEM SUZHOU	Mold Compound:	SID#44	41086		
# Pins-Designator, Family:	32-RHB, VQFN	Mount Compound:	SID#43	35143		
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	1.3 Mil Dia., Cu			
Qualification: 🗌 Plan 🛛 Test Results						
Reliability Test	Conditions	Conditions		Sample Size/Fail		
Reliability rest	Conditions		Lot#1	Lot#2	Lot#3	
**High Temp. Storage Bake	170C (420hrs)	170C (420hrs)		77/0	77/0	
**Biased HAST	130C/85%RH (9	130C/85%RH (96hrs)		77/0	77/0	
**Autoclave 121C	121C, 2 atm (96	121C, 2 atm (96 Hrs)		77/0	77/0	
**T/C -65C/150C	-65C/+150C (50	-65C/+150C (500 Cyc)		77/0	77/0	
Manufacturability	(per mfg. Site specification)		Pass	Pass	Pass	
Moisture Sensitivity	(level 2 @ 260C peak +5/-0C)		12/0	12/0	12/0	
Notes **- Preconditioning sequence: Level 3-260C.						

Qual Vehicle #2: TPA6132A2RTER (MSL2-260C)							
Package Construction Details							
Assembly Site:	CARSEM SUZHOU	Mold Compound:	SID#441086				
# Pins-Designator, Family:	16-RTE, WQFN	Mount Compound:	SID#43	SID#435933			
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.96 M	il Dia., Cu	I		
Qualification: Plan I Test Results							
Deliability Test	Conditions		San	Sample Size/Fail			
Reliability Test	Conditions		Lot#	1	Lot#2		
**Autoclave 121C	121C, 2 atm (96	Hrs)	77/0)	77/0		
**T/C -65C/150C	-65C/+150C (50	-65C/+150C (500 Cyc))	77/0		
Manufacturability		(per mfg. Site specification)		5	-		
Notes **- Preconditioning sequence: Level 2-260C.							
Qua	I Vehicle # 3: TPS2	540RTER (MSL2-260	C)				
	Package Const	ruction Details					
Assembly Site:	CARSEM SUZHOU	Mold Compound:	SID#441086				
# Pins-Designator, Family:	16-RTE, WQFN	Mount Compound:	SID#435143				
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	1.98 M	il Dia., Cu	I		
Qualification: 🗌 Plan	Qualification: 🗌 Plan 🛛 Test Results						
Reliability Test	Conditions	Canditiana		Sample Size/Fail			
	Conditions		Lot#1	Lot#2	Lot#3		
High Temp Life Test	125C (168 Hrs)	125C (168 Hrs)		80/0	80/0		
**T/C -65C/150C	-65C/+150C (50	О Сус)	77/0	77/0	-		
Notes **- Preconditioning sequence: Level 2-260C.							

Reference Qualification Data

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

Qual Vehicle # 1: 2ELVC412CDRTJR (MSL2-260C)								
Package Construction Details								
Assembly Site:	CARSEM SUZHOU Mold Comp		und: SID#44108					
# Pins-Designator, Family:	20-RTJ, WQFN Mount Compo		nd: SID#435143					
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wi	re: 1.0	Mil Dia., C	1il Dia., Cu			
Qualification: 🗌 Plan 🛛 Test Results								
Reliability Test	Conditions	Conditions		Sample Size/Fail				
Reliability rest	Conditions		Lot#1	Lot#2	Lot#3			
**High Temp. Storage Bake	170C (420hrs)	170C (420hrs)		77/0	77/0			
**Autoclave 121C	121C, 2 atm (96 l	121C, 2 atm (96 Hrs)		77/0	77/0			
**T/C -65C/150C	-65C/+150C (500	-65C/+150C (500 Cyc)		77/0	77/0			
Manufacturability	(per mfg. Site specification)		Pass	Pass	Pass			
Moisture Sensitivity	(level 2 @ 260C p	(level 2 @ 260C peak +5/-0C)		-	-			
Notes **- Preconditioning sequence: Level 2-260C.								

Qual \	/ehicle # 2: ONET85	01PBRGTR (MSL2-26	50C)			
	Package Constr	uction Details	-			
Assembly Site:	CARSEM SUZHOU	Mold Compour	nd: SID	#441086		
# Pins-Designator, Family:	16-RGT, VQFN	Mount Compoun	nd: SID#435143			
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wir	re: 1.0	Mil Dia., C	Cu	
Qualification: 🗌 Plan	Test Results					
	Conditions	Conditions		Sample Size/Fail		
Reliability Test	Conditions			Lot#2	Lot#3	
**High Temp. Storage Bake	170C (420hrs)	170C (420hrs)		77/0	77/0	
**Autoclave 121C	121C, 2 atm (96	Hrs)	77/0	77/0	77/0	
**T/C -65C/150C	-65C/+150C (500		77/0	77/0	77/0	
Manufacturability (Assembly) (per mfg. Site spe	ecification)	Pass	Pass	Pass	
Moisture Sensitivity	(level 2 @ 260C p	beak +5/-0C)	12/0	-	-	
Notes **- Preconditioning	sequence: Level 2-26	0C.				
Qual	Vehicle # 3: TPS51	728RHAR (MSL3-260)C)			
	Package Constr	uction Details	-			
Assembly Site	e: CARSEM SUZHOU	Mold Compound:	SID#4	41086		
# Pins-Designator, Famil	y: 20-RTJ, VQFN	Mount Compound:	SID#435143			
Lead frame (Finish, Base		Bond Wire:				
Qualification: Plan	Test Results			- /		
Sample Size/Fail					'Fail	
Reliability Test	Conditions	Conditions		Lot#2	Lot#3	
**High Temp. Storage Bake	170C (420 Hrs)		Lot#1 77/0	77/0	77/0	
**Autoclave 121C	121C, 2 atm (96 F	lrs)	76/0	75/0	77/0	
**T/C -65C/150C	-65C/+150C (500		77/0	77/0	77/0	
Manufacturability	(per mfg. Site spe		Pass	Pass	Pass	
Moisture Sensitivity		(level 3 @ 260C peak +5/-0C)		-	-	
	sequence: Level 3-26		12/0			
		211RGTR (MSL2-260)C)			
	Package Constr	•	/ - /			
Assembly Site:	CARSEM SUZHOU	Mold Compound:	SID#4	41086		
# Pins-Designator, Family:						
Lead frame (Finish, Base):						
Qualification: Plan	NiPdAu, Cu Image: Test Results	Bond Wire:	1.0 Mil	Dia., Cu		
			Sar	nple Size/	'Fail	
Reliability Test	Conditions	Conditions		Lot#2	Lot#3	
**Biased HAST	130C/85%RH (96	130C/85%RH (96hrs)		76/0	77/0	
**High Temp. Storage Bake	170C (420hrs)			77/0	77/0	
**Autoclave 121C	· · · · · · · · · · · · · · · · · · ·	121C, 2 atm (96 Hrs)		77/0	77/0	
**T/C -65C/150C		-65C/+150C (500 Cyc)		77/0	77/0	
Manufacturability (Assembly		(per mfg. Site specification)		Pass	Pass	
Moisture Sensitivity	(level 2 @ 260C p		Pass 12/0	-	-	
	sequence: Level 2-26		-, -	1	1	

Qual Vehicle # 5: UCD9211RHAR (MSL3-260C)							
Package Construction Details							
Assembly Site:	CARSEM SUZHOU	ARSEM SUZHOU Mold Compound:		SID#441086			
# Pins-Designator, Family:	40-RHA, VQFN	Mount Compound:	SID#43	SID#435143			
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.8 Mil	Dia., Cu			
Qualification: 🗌 Plan	🛛 Test Results						
Reliability Test	Conditions	Conditions		Sample Size/Fail			
Reliability Test	Conditions		Lot#1	Lot#2	Lot#3		
**High Temp. Storage Bake	170C (420hrs)		77/0	77/0	77/0		
**Autoclave 121C	121C, 2 atm (96	121C, 2 atm (96 Hrs)		77/0	77/0		
**T/C -65C/150C	-65C/+150C (500	-65C/+150C (500 Cyc)		77/0	77/0		
Salt Atmosphere	24 hrs	24 hrs		22/0	22/0		
Manufacturability (Assembly) (per mfg. Site spe	(per mfg. Site specification)		Pass	Pass		
Moisture Sensitivity	(level 3 @ 260C p	(level 3 @ 260C peak +5/-0C)		-	-		
Notes **- Preconditioning sequence: Level 3-260C.							

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com